

Search Not s



Application No.

10/647,265

Examiner

D. Rutledge

Applicant(s)

SUGITA, MITSURO

Art Unit

2851

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
355	53,67-69	6/24/2004	DR
430	5, 311	6/24/2004	DR
250	491.1	6/24/2004	DR
250	492.2	6/24/2004	DR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
(reticle or mask) and substra; path adj length same difference same path near4 (pattern or translucent) same path near2 space	6/24/2004	DR
f(irst or second) near3 (transmission or transmitting) adj (factor or parameter) same (mask or reticle or pattern),	6/24/2004	DR
(expos\$3 or transfer\$4) near2 (pattern or image or mask or reticle)	6/24/2004	DR
Derwent, EPO, JPO	6/24/2004	DR